

**Search Notes**

Application/Control No.

10/825,528

Examiner

Anthony Weier

Applicant(s)/Patent under  
Reexamination

SHEN ET AL.

Art Unit

1761

**SEARCHED**

Class	Subclass	Date	Examiner
updated	previous search	3/2/2007	AW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR